

ROCKY: A Robust Hybrid On-chip Memory Kit For The Processors With STT-MRAM Cache Technology

Mahdi Talebi, Arash Salahvarzi, Amir Mahdi Hosseini Monazzah, Kevin Skadron, And
Mahdi Fazeli



Arash Salahvarzi

RA @ CPS-Lab

IUST

Arash_salahvarzi@alumni.iust.ac.ir

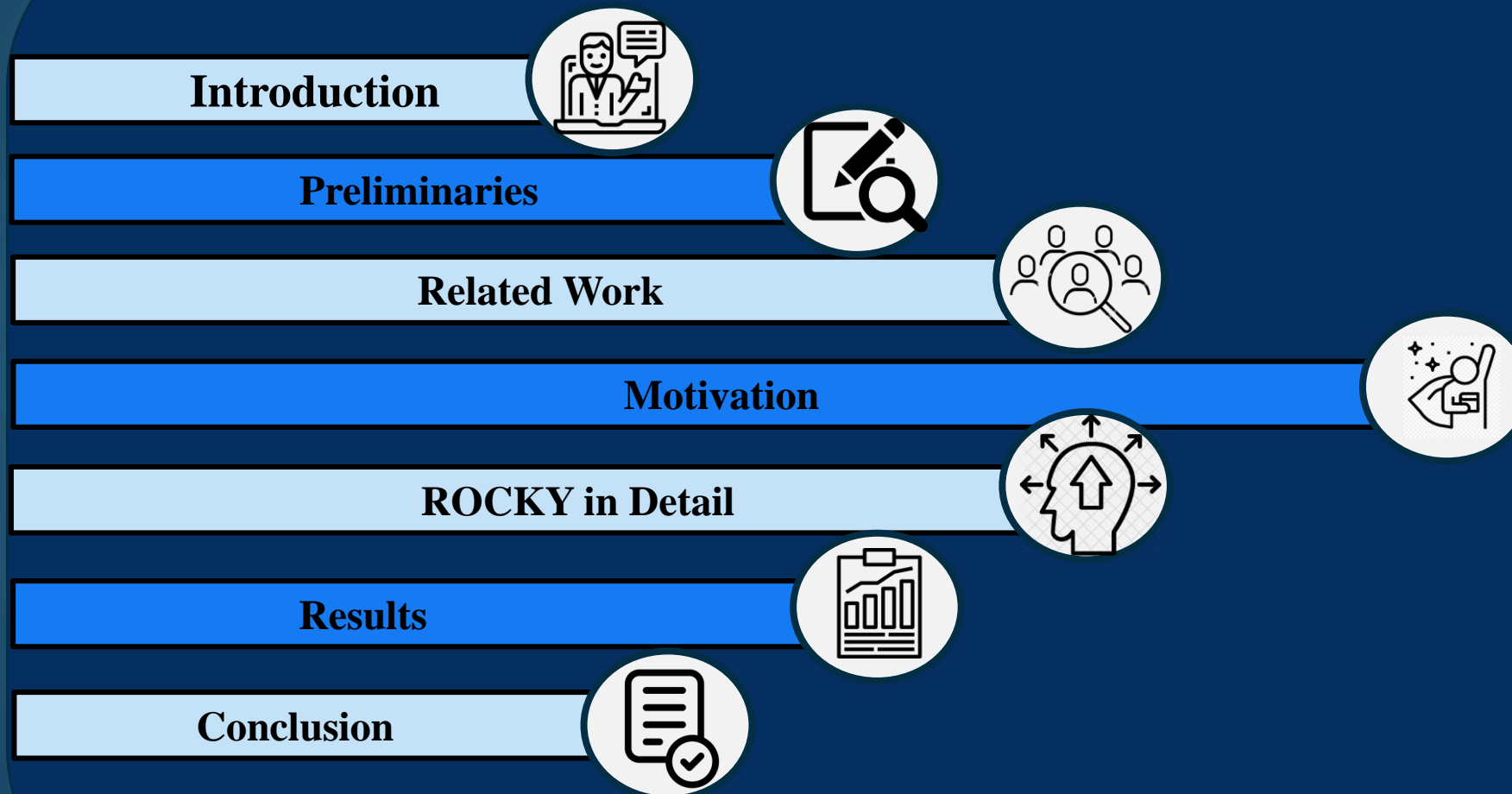


Cyber-Physical Systems
Laboratory

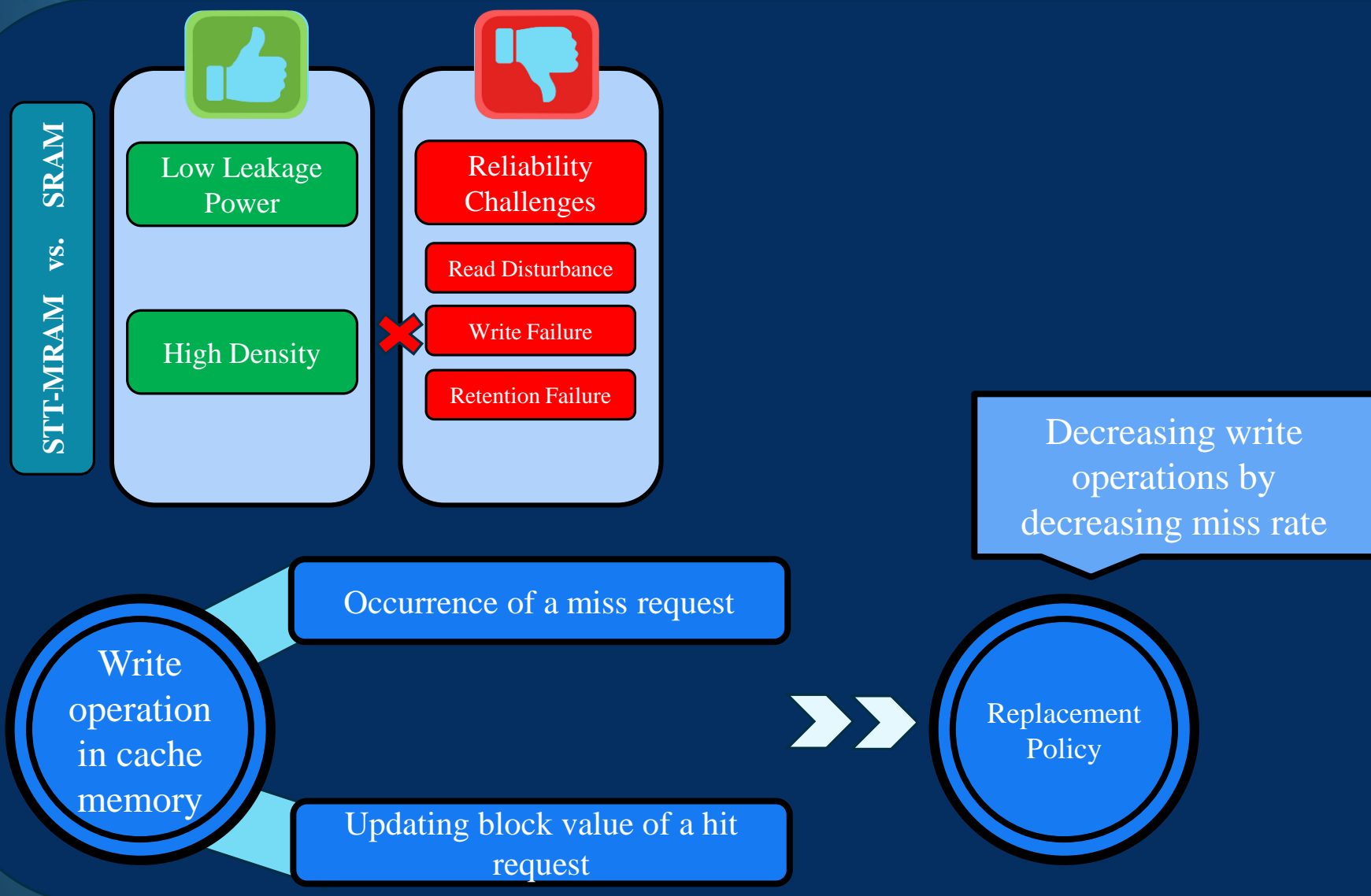


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Science and Technology

Outline



- Introduction
- Preliminaries
- Related Work
- Motivation
- ROCKY
- Results
- Conclusion



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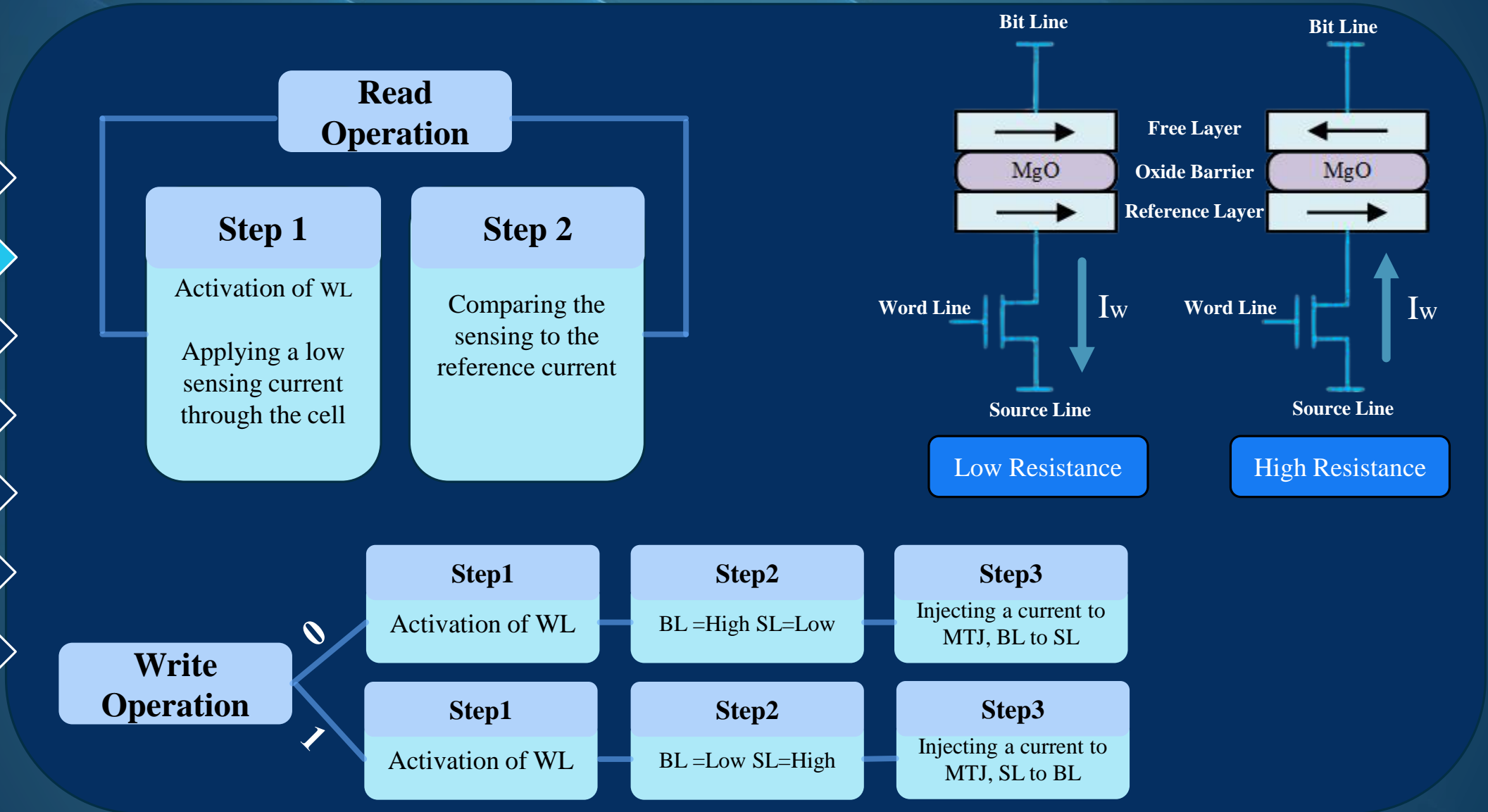
The Main Contributions

Exploring the effects of different replacement policies on the reliability of STT-MRAM caches

Proposing a set of replacement policies which are efficiently coupled with each other

Design and evaluating the underlying cache memory hierarchy architecture to utilize the proposed replacement policies.

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Read Failure

- Applied read current higher than the critical switching current
- Changing the content of the cell unwantedly
- $P_{RD}(t_r) = 1 - \exp\left(\frac{-t_r}{\tau} \times \exp\left(\frac{-\Delta(I_r - I_{C0})}{I_{C0}}\right)\right)$

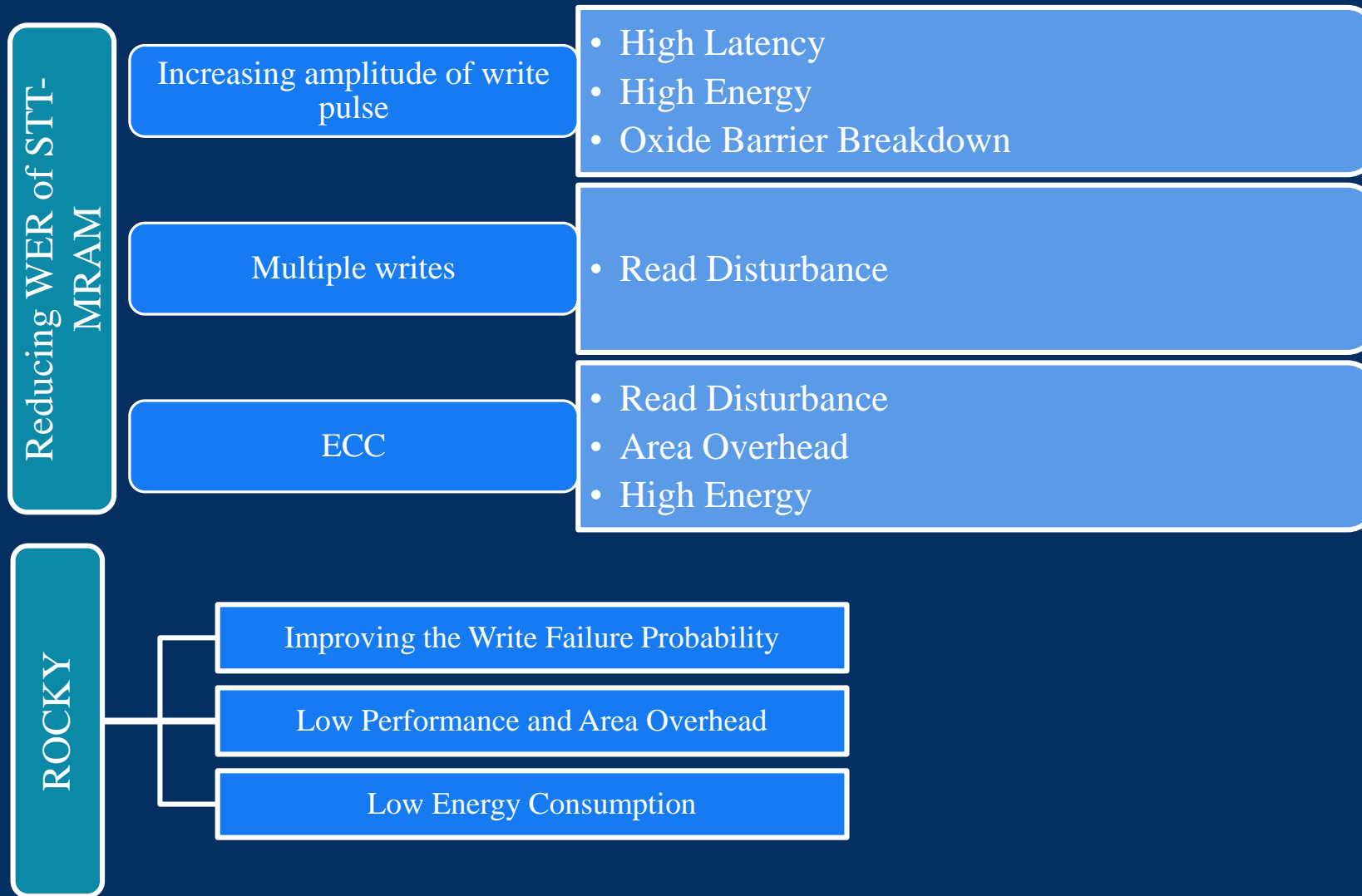
Retention Failure

- Changing the content of STT-MRAM after being idle for a time
- $P_{RF}(t) = 1 - \exp\left(\frac{-t}{\exp(\Delta)}\right)$

Write Failure

- A write current signal period shorter than the MTJ switching time
- $P_{WF}(t_w) = \exp\left(-t_w \times \frac{2\mu_B P(I_w - I_{C0})}{(c + \ln(\pi^2 \frac{\Delta}{4})) \times (em(1+p^2))}\right)$

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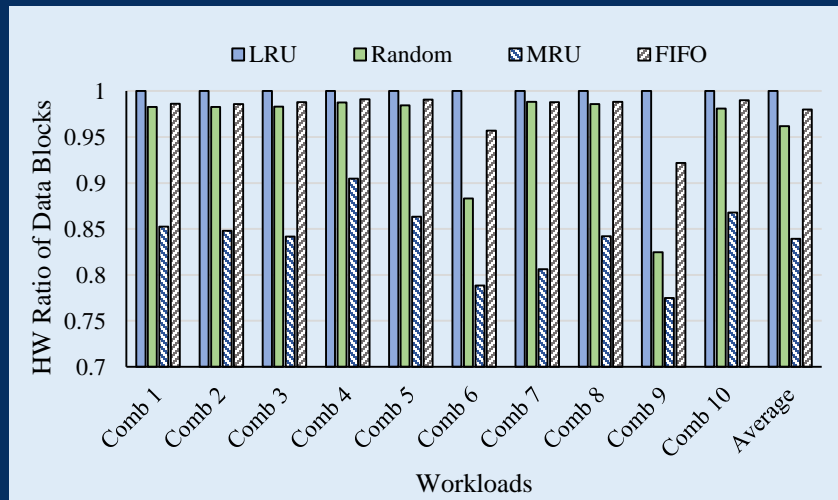
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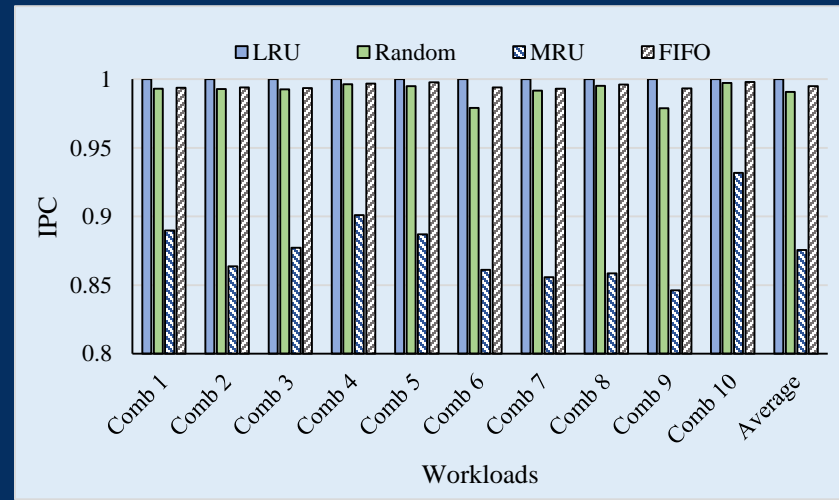
Higher switching time of $0 \rightarrow 1$ compared to $1 \rightarrow 0$



$0 \rightarrow 1 \propto$ Hamming Weight



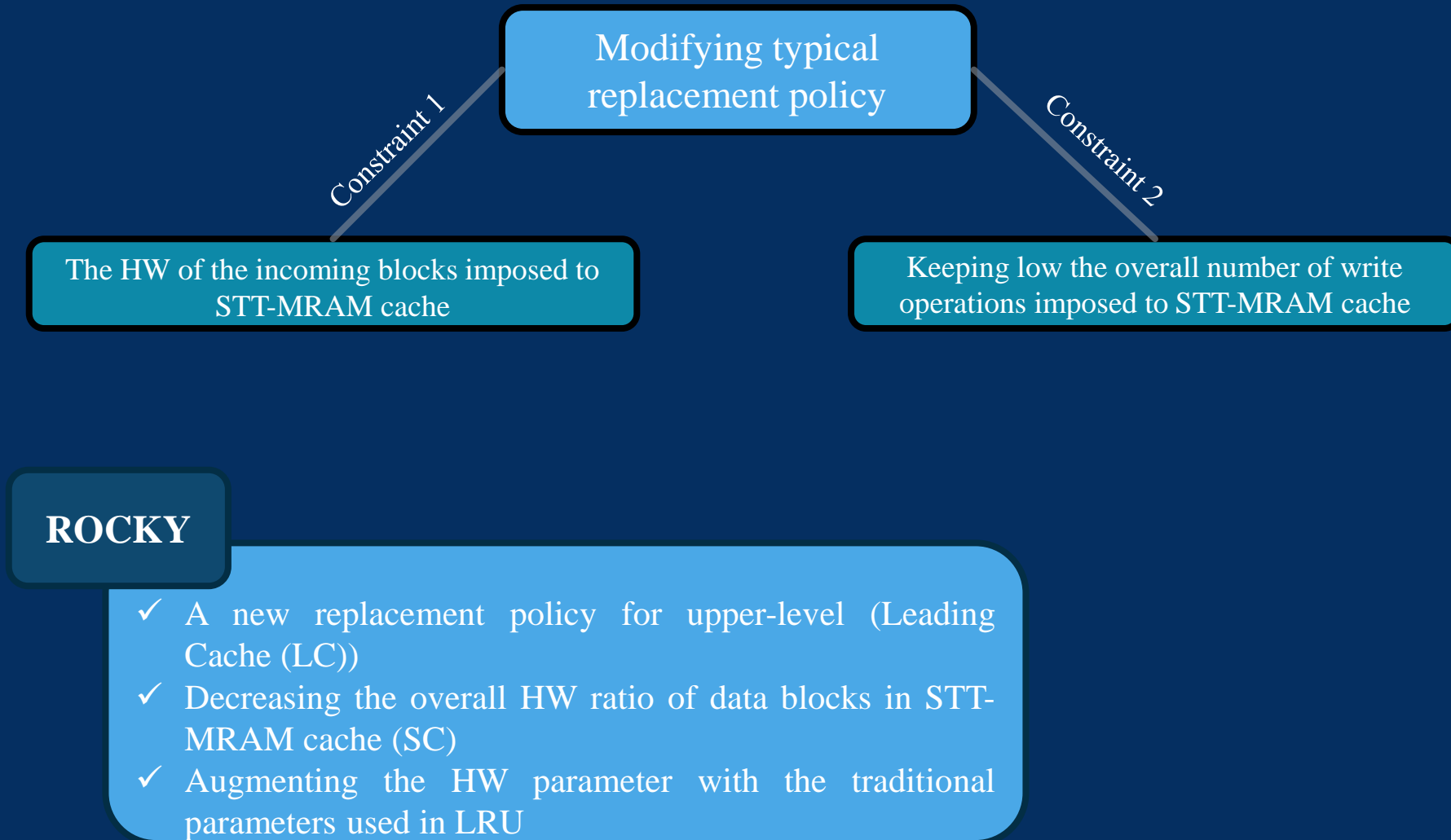
HW ratio of L2 cache incoming data blocks, normalized to LRU

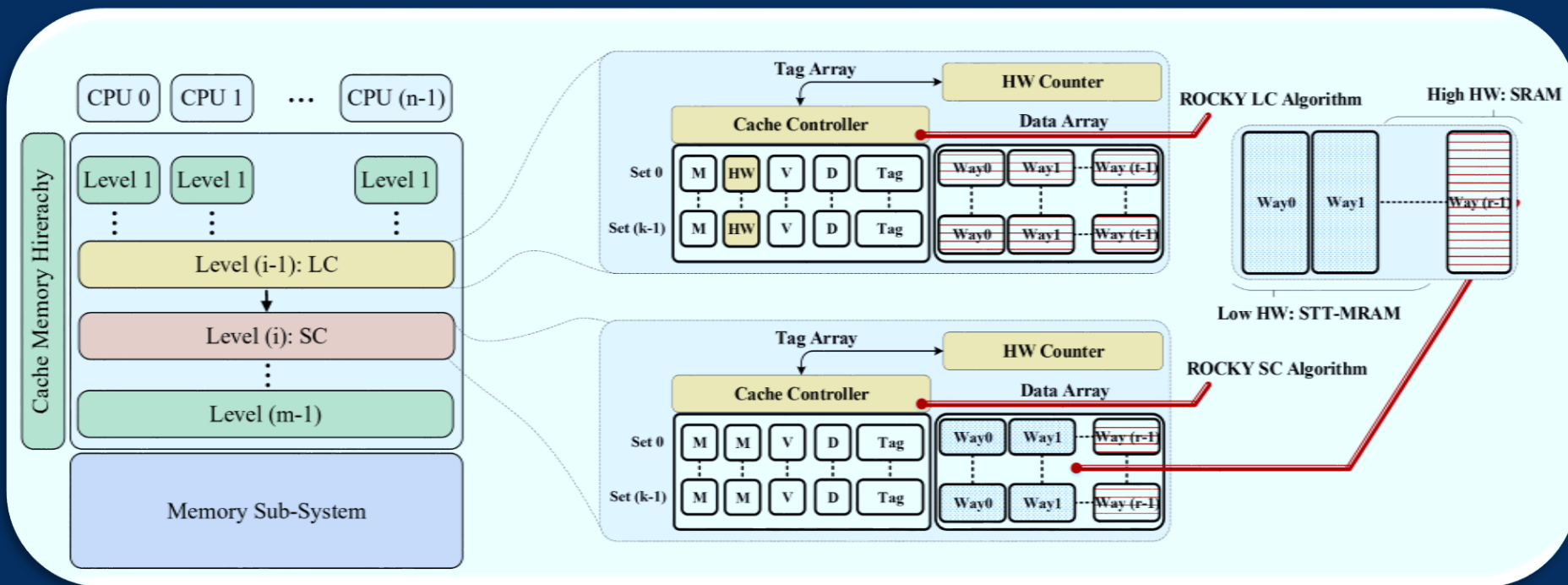


IPC of selected replacement policies for level one cache, normalized to LRU

gem5 full-system simulator

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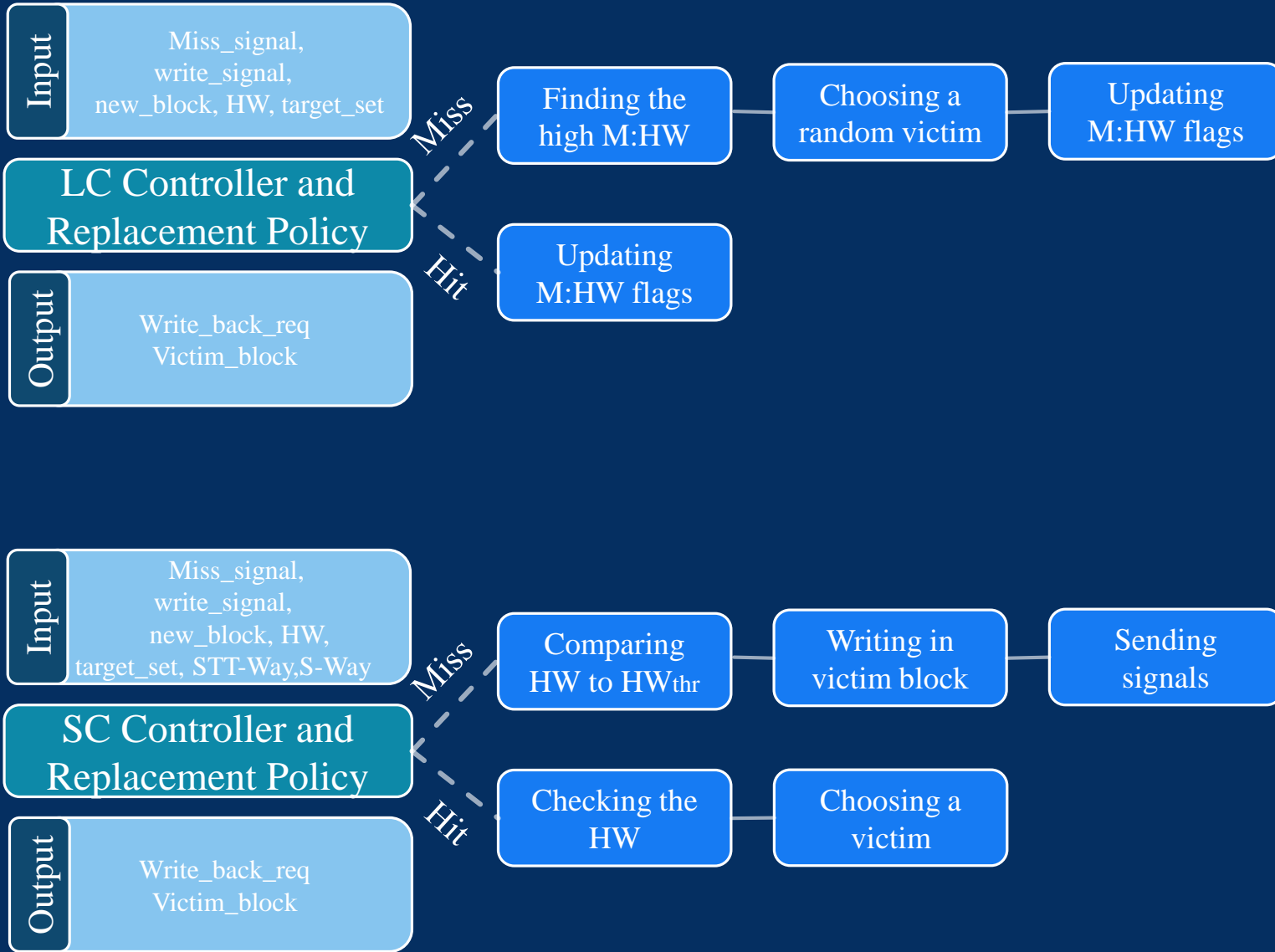


HW Counter	Counting the HW of each block
HW Flag	Keeping the basic information about the HW of block
Cache Controller	Implementing the ROCKY replacement policy

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Simulations Configurations

Component	Parameter	Value
Processor	Architecture	ARM
	Frequency	1GHz
	Number of Cores	4
	Type	Homogeneous
	Model	Detailed
	Warmup Cycles	100 millions cycles
L1 Cache	Memory Technology	SRAM
	Size	32KB
	Associativity	4
	Block Size	64B
	Access Time	2 cycles
	Replacement Policy	ROCKY LC
L2 Cache (Hybrid)	Memory Technology	STT-MRAM+SRAM
	Size	4MB (3584KB +512KB)
	Associativity	16 (14 way + 2 way)
	Block Size	64B
	STT-MRAM Access Time	Write 20 and Read 5 cycles
	SRAM Access Time	5 cycles
	Replacement Policy	ROCKY SC
	STT-MRAM Energy per Read	0.210 nJ
	STT-MRAM Energy per Write	1.01 nJ
	SRAM Energy per Access	0.240 nJ
Main Memory	Memory Technology	DRAM DDR3
	Size	4GB
	Access Time	100 cycles

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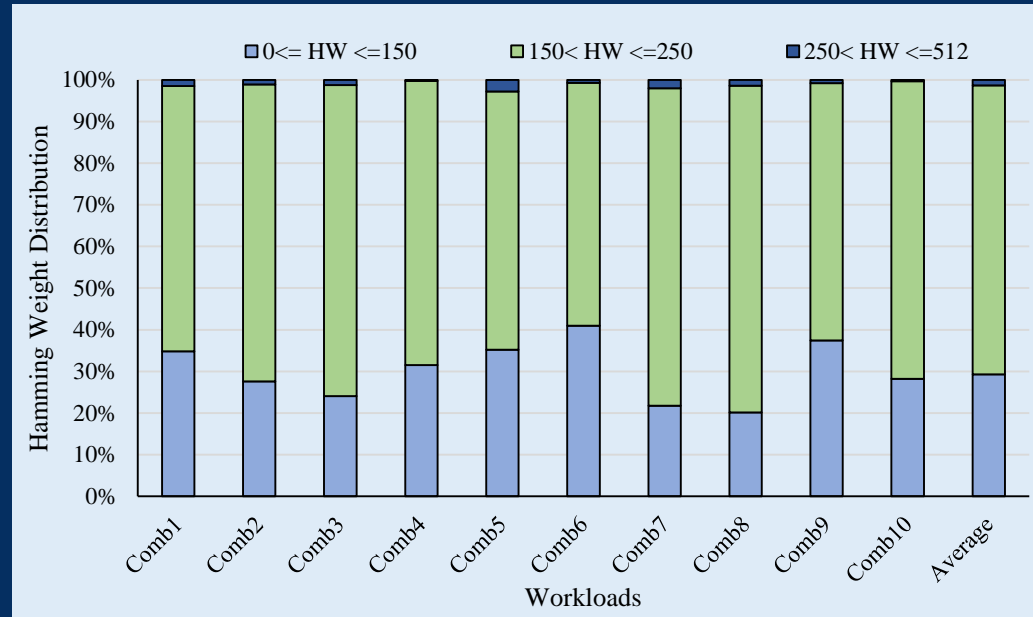
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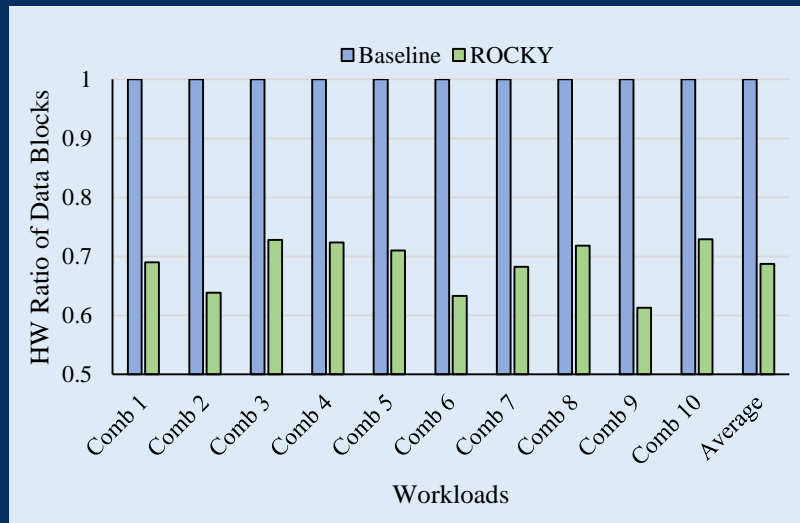
Conclusion



10 combinations from SPEC CPU2006 benchmarks

HW_{thr} as a knob for ROCKYHigh HW_{thr} → High write error rate

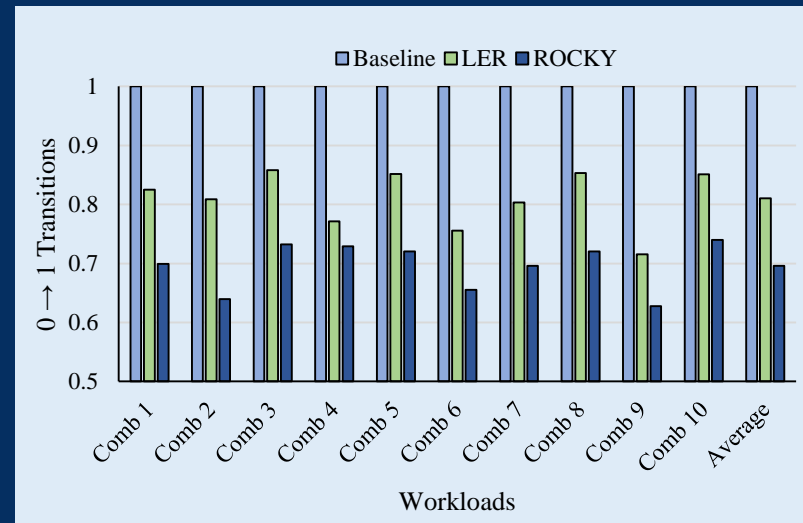
Reliability



HW ratio of L2 cache, normalized to the baseline

Reducing HW Ratio

ROCKY	LER
31.3%	0%

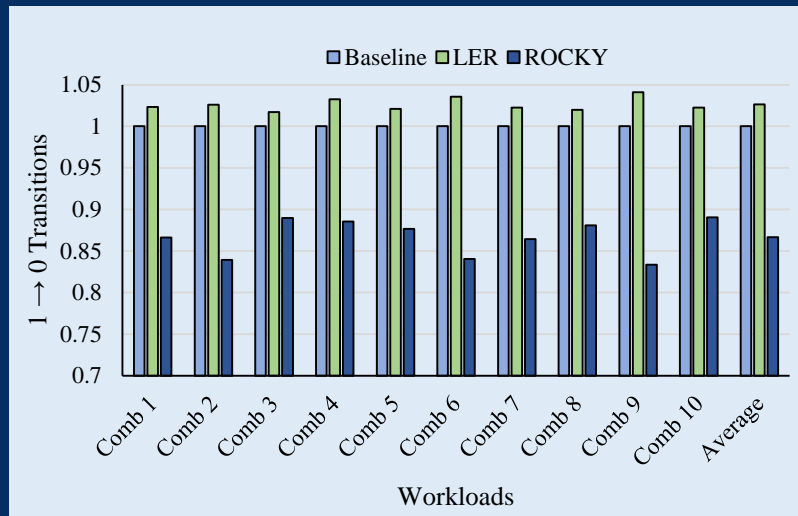


0 → 1 transitions in L2 cache, normalized to the baseline

Reducing 0→1 Transitions

ROCKY	LER
30.5%	19%

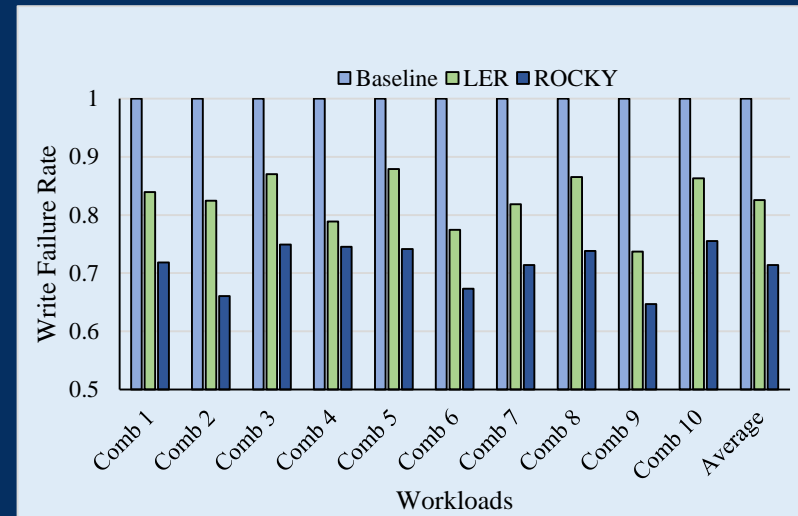
Reliability



1 → 0 transitions in L2 cache, normalized to the baseline

Reducing 1→0 Transitions

ROCKY	LER
11.7%	-2.6%

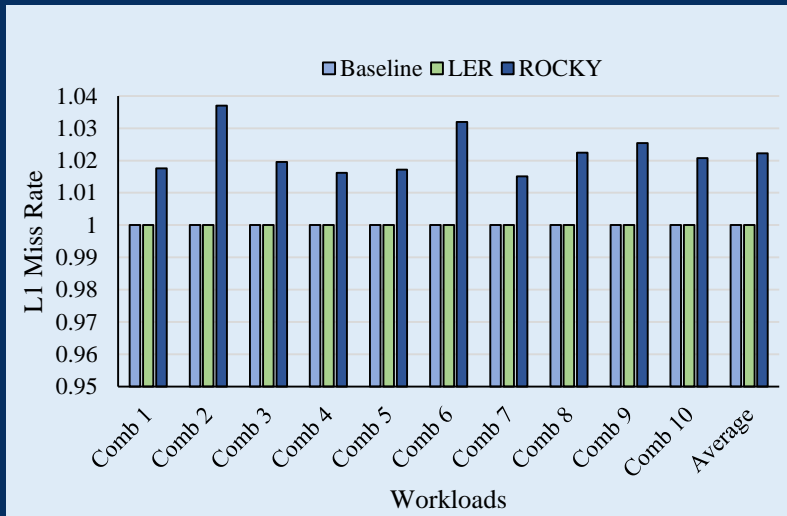


WER in L2 cache, normalized to the baseline

Reducing WER

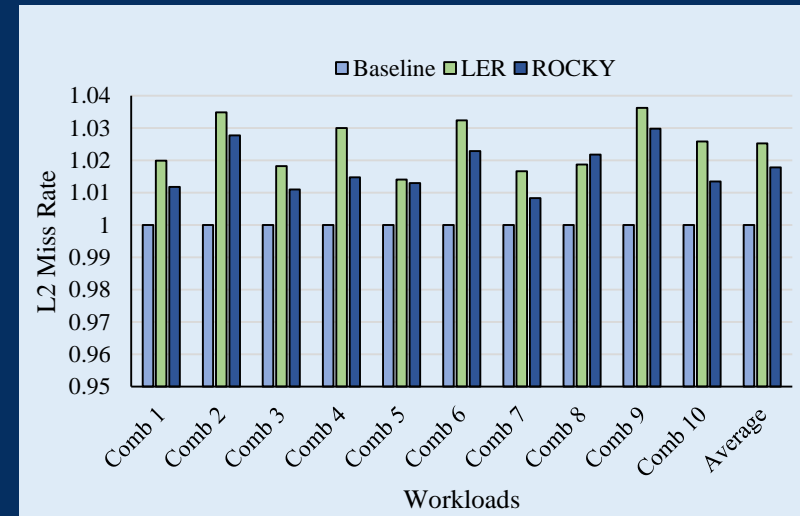
ROCKY	LER
28.7%	17.5%

Performance



Miss rate of L1 cache, normalized to the baseline

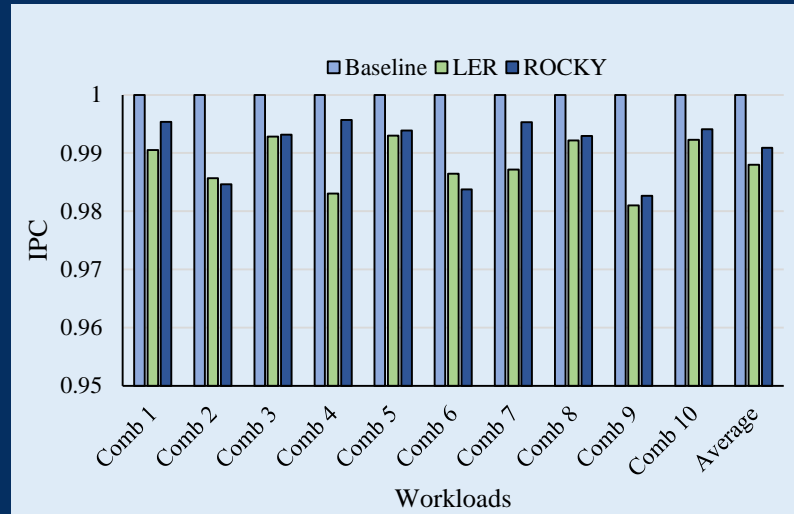
Imposed Miss Rate	
ROCKY	LER
2.2%	0%



Miss rate of L2 cache, normalized to the baseline

Imposed Miss Rate	
ROCKY	LER
1.8%	2.4%

Performance



Normalized IPC to the baseline

IPC Overhead	
ROCKY	LER
0.9%	1.2%

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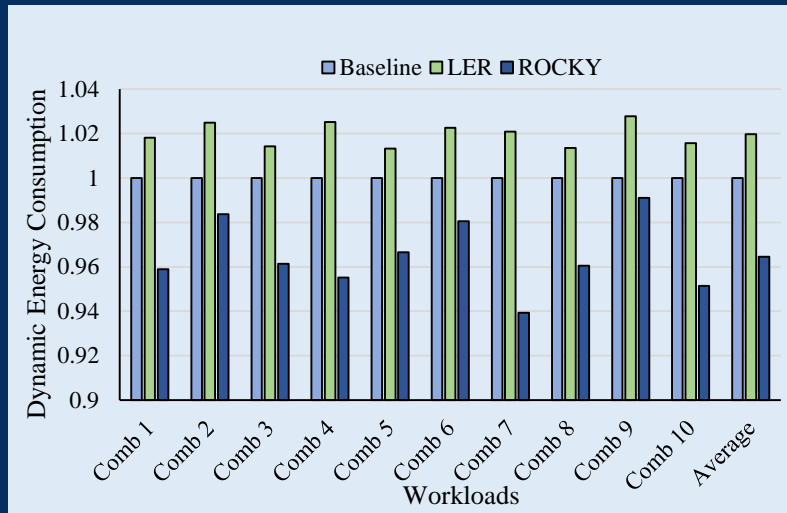
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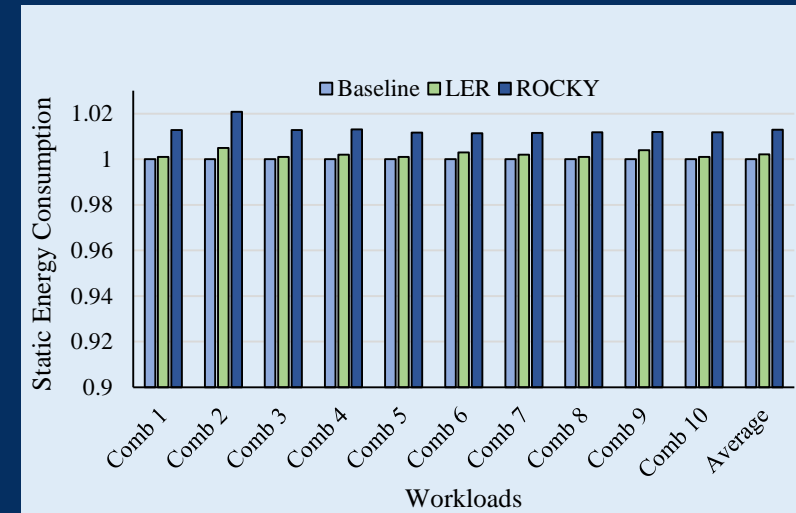
Conclusion

Energy Consumption



Dynamic energy consumption of L2 cache, normalized to the baseline

Dynamic Energy Consumption	
ROCKY	LER
-3.55%	1.9%

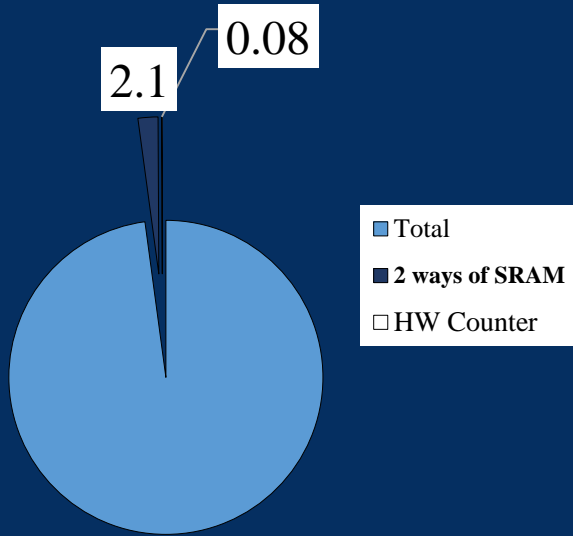


Static energy consumption of L2 cache, normalized to the baseline

Imposed Static Energy	
ROCKY	LER
1.3%	0.2%

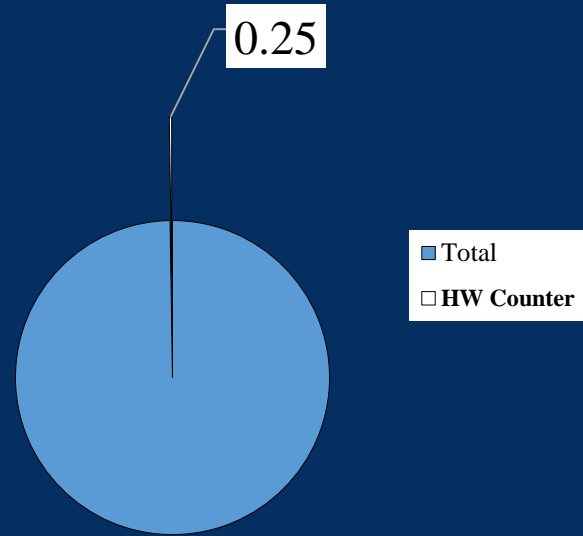
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Area



L2 Cache

- 2 Ways of SRAM → 2.1%
- HW Counter → 0.08%



L1 Cache

- HW Counter → 0.25%

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01 High Leakage power and low density of SRAM

02 Advantages of STT-MRAM

03 Reliability challenges of STT-MRAM

04 0→1 transitions in write patterns

05 Reducing HW ratio of data blocks using ROCKY

06 Reduction of write failure by 28.7%

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**THANK
YOU**



**Room 121, Department of Computer Engineering, Iran University of Science and Technology,
University Road, Hengam Street, Resalat Square, Narmak, Tehran, IRAN 16846-13114.**



+98 (21) 73225350



cps.iust.ac.ir